Acta Crystallographica Section E

## Structure Reports

Online
ISSN 1600-5368

Peter G. Jones, ${ }^{\text {a }}{ }^{*}$ Harald Berger, ${ }^{\text {b }}$
Peter Bubenitschek ${ }^{\text {b }}$ and Henning Hopf ${ }^{\text {b }}$
${ }^{\mathrm{a}}$ Institut für Anorganische und Analytische Chemie, Technische Universität Braunschweig, Postfach 3329, 38023 Braunschweig, Germany, and ${ }^{\mathbf{b}}$ Institut für Organische Chemie, Technische Universität Braunschweig, Postfach 3329,
38023 Braunschweig, Germany
Correspondence e-mail: p.jones@tu-bs.de

## Key indicators

Single-crystal X-ray study
$T=203 \mathrm{~K}$
Mean $\sigma(\mathrm{C}-\mathrm{C})=0.005 \AA$
$R$ factor $=0.060$
$w R$ factor $=0.137$
Data-to-parameter ratio $=16.2$
For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.
(C) 2004 International Union of Crystallography Printed in Great Britain - all rights reserved

## 10,10-Bis(trimethylsilylethynyl)-9-methylenefluorene

In the title compound \{systematic name: 9-[bis(trimethylsilylethynyl)methylene]fluorene\}, $\mathrm{C}_{24} \mathrm{H}_{26} \mathrm{Si}_{2}$, the molecules are planar (except for the methyl groups) and pack in layers parallel to the $b c$ plane at $x \simeq \frac{1}{4}$ and $\frac{3}{4}$. The mean distance between neighbouring layers, which are related by inversion, is $3.50 \AA$.

## Comment

As we have recently shown (Eshdat et al., 2002), 1,1diethynylethenes (2-ethynylbut-1-en-3-ynes) undergo a novel cyclization to fulvalenes when subjected to reducing conditions (potassium in tetrahydrofuran). To generalize this process, we have prepared the fluorene derivative (3) (see Experimental), which was characterized by spectroscopic data and the structure determination described here.


The molecule is shown in Fig. 1. The molecular dimensions are normal. Except for the methyl groups, the molecule is essentially planar (r.m.s. deviation of non-H atoms is $0.02 \AA$ ).


Figure 1
The molecule of (3). Displacement ellipsoids are drawn at the $50 \%$ probability level. H-atom radii are arbitrary.

Received 23 February 2004 Accepted 25 February 2004 Online 6 March 2004


Figure 2
Packing diagram of (3), projected parallel to the $a$ axis, showing one layer and (top right) the overlap with one molecule of the next layer, drawn with thinner bonds. H atoms have been omitted for clarity; radii are arbitrary.

The molecules pack in layers parallel to the $b c$ plane, to which the molecular plane of the asymmetric unit makes an angle of $5.2^{\circ}$, at $x \simeq \frac{1}{4}$ and $\frac{3}{4}$ (Fig. 2). The mean distance between neighbouring layers, which are related by inversion, is $a / 2=3.50 \AA$. There are no unusually short intermolecular contacts.

Jones et al. (2004) describe a TCNQ adduct of the title compound.

## Experimental

Compound (3) was prepared in $83 \%$ yield by Peterson olefination of the doubly protected ketone (2) with 9-trimethylsilylfluorene, (1), using $n$-butyllithium as base in diethyl ether (Berger, 2004). Single crystals were obtained by slow cooling of solutions of (3) in methanol.

## Crystal data

$$
\begin{aligned}
& \mathrm{C}_{24} \mathrm{H}_{26} \mathrm{Si}_{2} \\
& M_{r}=370.63 \\
& \text { Monoclinic, } P 2_{1} / n \\
& a=7.003(2) \AA \\
& b=13.219(2) \AA \\
& c=23.779(4) \AA \\
& \beta=91.64(3)^{\circ} \\
& V=2200.4(8) \AA^{3} \\
& Z=4
\end{aligned}
$$

## Data collection

Stoe Stadi-4 diffractometer $\omega / \theta$ scans

$$
\begin{aligned}
& \theta_{\max }=25.1^{\circ} \\
& h=-8 \rightarrow 8 \\
& k=-15 \rightarrow 0 \\
& l=-28 \rightarrow 28
\end{aligned}
$$

Absorption correction: none 8747 measured reflections 3894 independent reflections 2212 reflections with $I>2 \sigma(I)$ $R_{\text {int }}=0.071$

3 standard reflections frequency: 60 min intensity decay: none

## Refinement

Refinement on $F^{2}$

$$
\begin{aligned}
& w=1 /[ \sigma^{2}\left(F_{o}{ }^{2}\right)+(0.0398 P)^{2} \\
&+0.8683 P] \\
& \text { where } P=\left(F_{o}{ }^{2}+2 F_{c}{ }^{2}\right) / 3 \\
&(\Delta / \sigma)_{\max }=0.001 \\
& \Delta \rho_{\max }=0.18 \mathrm{e} \AA^{-3} \\
& \Delta \rho_{\min }=-0.26 \mathrm{e}^{-3}
\end{aligned}
$$

$R\left[F^{2}>2 \sigma\left(F^{2}\right)\right]=0.060$
$w R\left(F^{2}\right)=0.137$
$S=1.01$
3894 reflections
241 parameters
H-atom parameters constrained

Table 1
Selected geometric parameters $\left(\AA{ }^{\circ},^{\circ}\right)$.

| $\mathrm{C} 11-\mathrm{C} 12$ | $1.194(4)$ | $\mathrm{C} 11^{\prime}-\mathrm{C} 12^{\prime}$ | $1.192(4)$ |
| :--- | :--- | :--- | :--- |
|  |  |  |  |
| $\mathrm{C} 12-\mathrm{C} 11-\mathrm{C} 10$ | $179.0(4)$ | $\mathrm{C} 12^{\prime}-\mathrm{C} 11^{\prime}-\mathrm{C} 10$ | $176.9(3)$ |
| $\mathrm{C} 11-\mathrm{C} 12-\mathrm{Si}$ | $173.3(3)$ | $\mathrm{C} 11^{\prime}-\mathrm{C}_{1}^{\prime}-\mathrm{Si}^{\prime}$ | $175.2(3)$ |

Methyl H atoms were located in difference syntheses, idealized $\left(\mathrm{C}-\mathrm{H}=0.98 \AA\right.$ and $\left.\mathrm{H}-\mathrm{C}-\mathrm{H}=109.5^{\circ}\right)$ and treated as rigid groups allowed to rotate but not tip. Other H atoms were placed at calculated positions and included in the refinement as riding, with $\mathrm{C}-\mathrm{H}$ bond lengths of $0.95 \AA$; $U_{\text {iso }}(\mathrm{H})$ values were fixed at $1.2 U_{\text {eq }}$ of the parent atom. Because the data were weak, restraints were applied to the displacement parameters of all non- H atoms and to the geometry (similarity of the two chemically equivalent halves of the molecule).

Data collection: DIF4 (Stoe \& Cie, 1992); cell refinement: DIF4; data reduction: REDU4 (Stoe \& Cie, 1992); program(s) used to solve structure: SHELXS97 (Sheldrick, 1990); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: XP (Siemens, 1994); software used to prepare material for publication: SHELXL97.

We thank Mr A. Weinkauf for technical assistance.

## References

Berger, H. (2004). PhD thesis. Technical University of Braunschweig, Germany.
Eshdat, L., Berger, H., Hopf, H. \& Rabinovitz, M. (2002). J. Am. Chem. Soc. 124, 3822-3823.
Jones, P. G., Berger, H., Bubenitschek, P. \& Hopf, H. (2004). Acta Cryst. E60, o492-o493..
Sheldrick, G. M. (1990). Acta Cryst. A46, 467-473.
Sheldrick, G. M. (1997). SHELXL97. University of Göttingen, Germany.
Siemens (1994). XP. Version 5.03. Siemens Analytical X-ray Instruments, Madison, Wisconsin, USA.
Stoe \& Cie (1992). DIF4 and REDU4. Stoe \& Cie, Darmstadt, Germany.

